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(12) **United States Design Patent**
Oonuma et al.

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(54) **PORTION OF AN ELECTRON MICROSCOPE**

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(*) Notice: This patent is subject to a terminal disclaimer.

(**) Term: **14 Years**

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(30) **Foreign Application Priority Data**

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(51) **LOC (9) Cl.** **16-06**

(52) **U.S. Cl.** **D16/131**

(58) **Field of Classification Search** D16/130, D16/131, 221, 234; D24/186, 232, 216, D24/233; D10/81; D13/184; 250/311; 359/383, 359/384, 385, 389, 390, 368, 370, 371, 372, 359/363; D7/601, 609, 323, 328, 350.1, D7/350.2, 350.3; 312/114, 117, 138.1, 351; D6/627; 206/558

See application file for complete search history.

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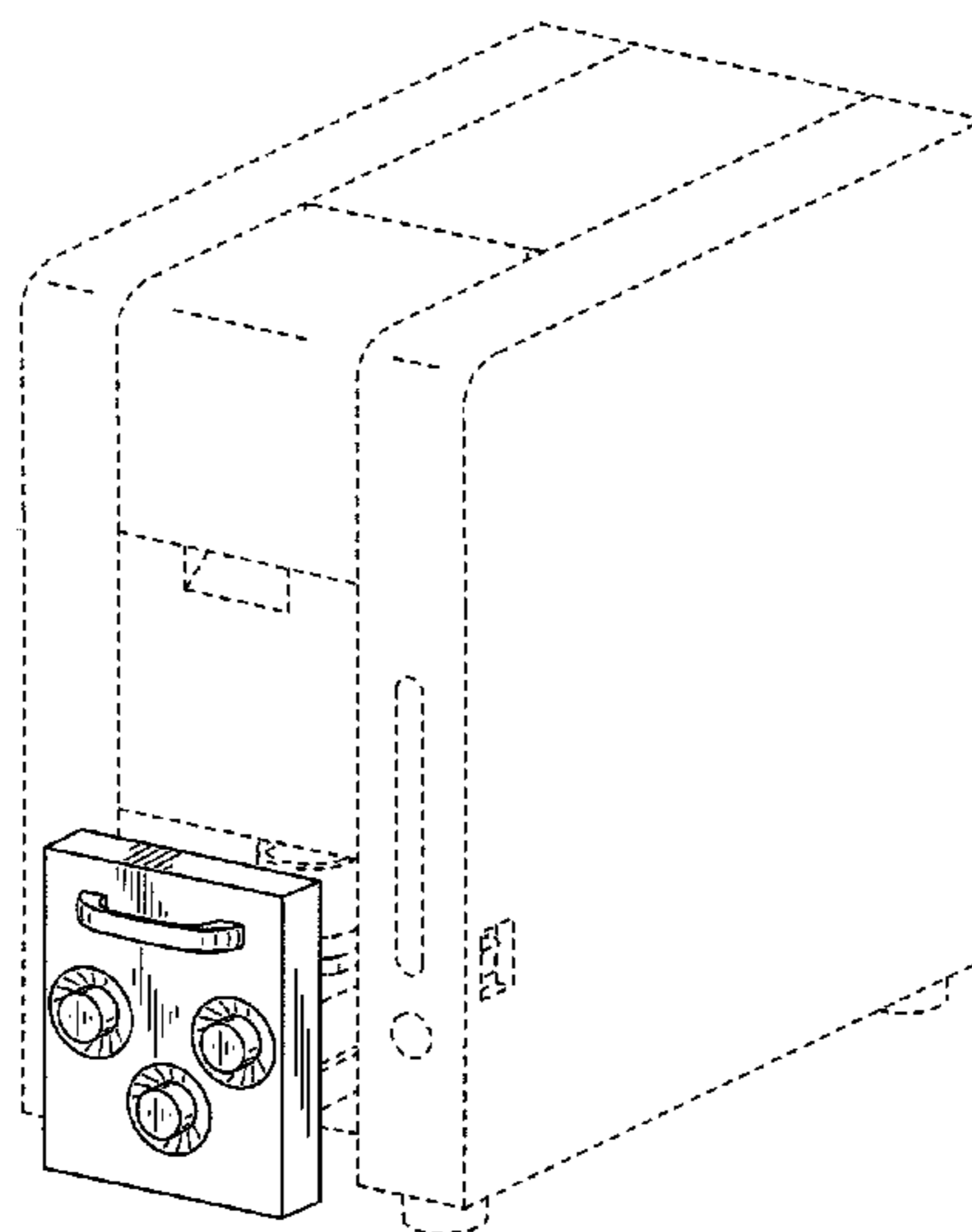
(57) **CLAIM**

We claim the ornamental design for a portion of an electron microscope, as shown and described.

DESCRIPTION

FIG. 1 is a front, top and right side perspective view of a portion of an electron microscope showing our new design; FIG. 2 is a front elevational view thereof; the rear view is not part of the claimed design; FIG. 3 is a rear elevational view thereof; FIG. 4 is a left side elevational view thereof; FIG. 5 is a right side elevational view thereof; FIG. 6 is a top plan view thereof; FIG. 7 is a bottom plan view thereof; and, FIG. 8 is a front, top and right side perspective view thereof shown in an opened positioned; the front, top and left side perspective view of the claimed design (shown in solid lines) is a mirror image of the claimed design as shown in FIG. 8. The broken lines shown are for illustrative purpose and form no part of the claimed design.

1 Claim, 8 Drawing Sheets



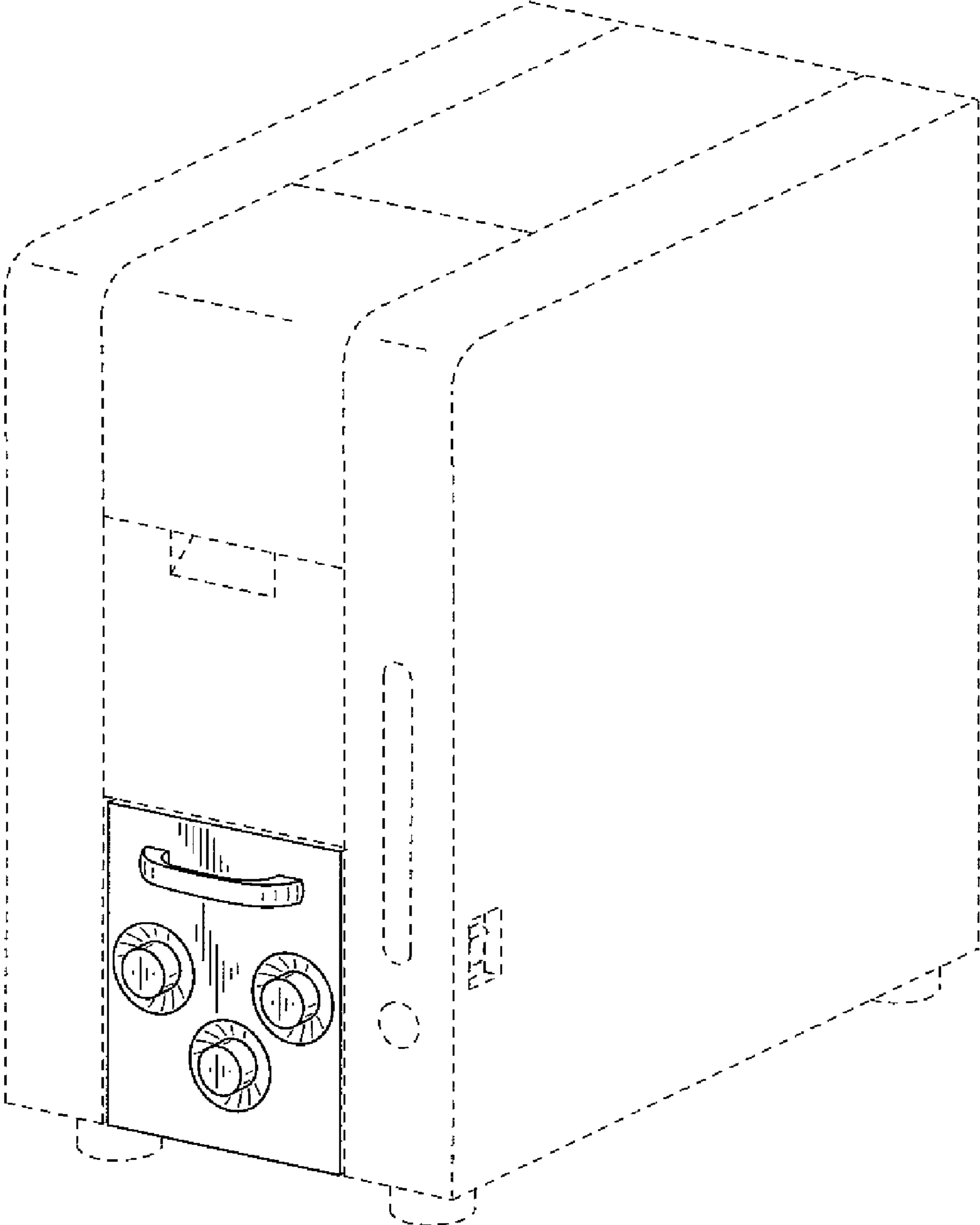


FIG. 1

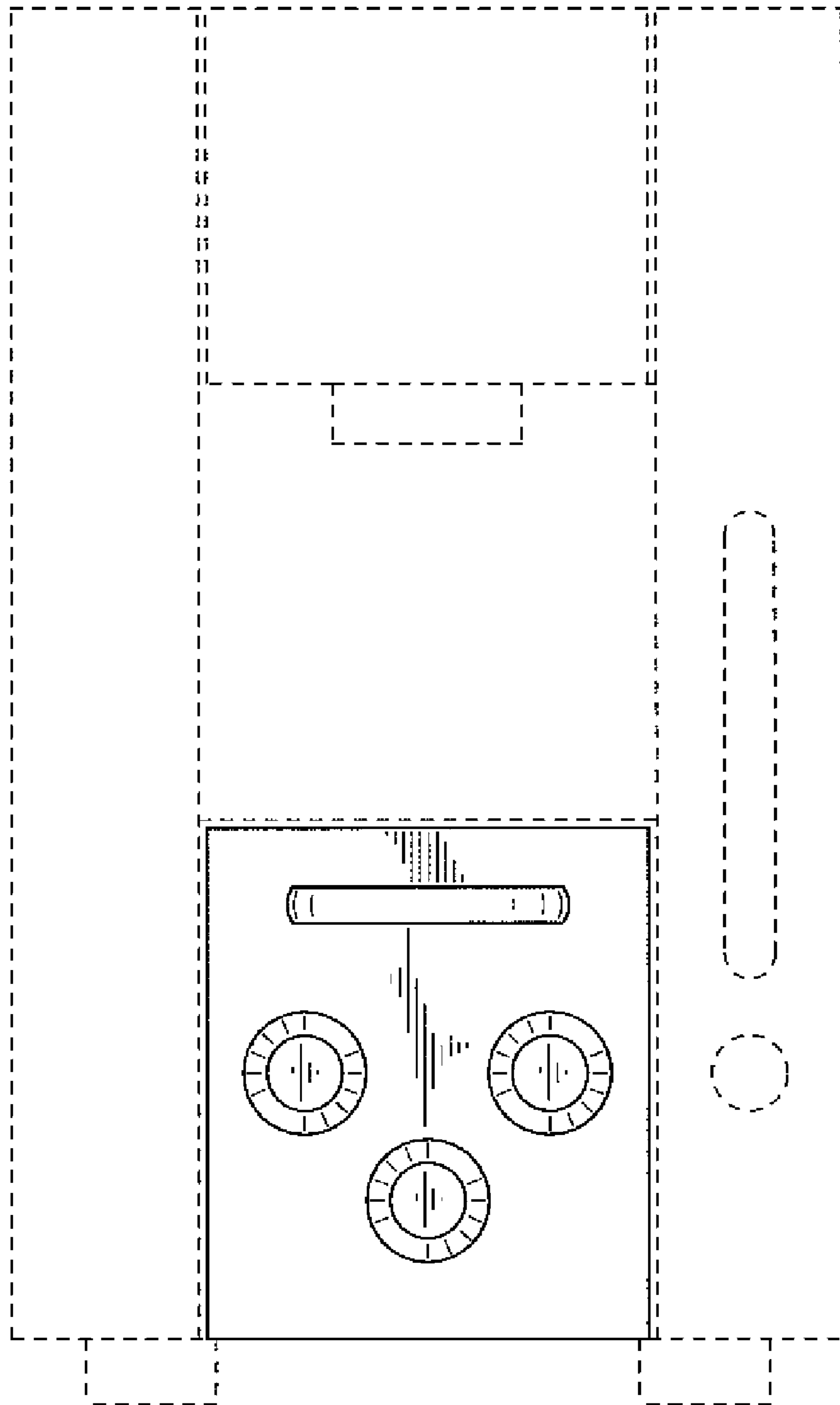


FIG. 2

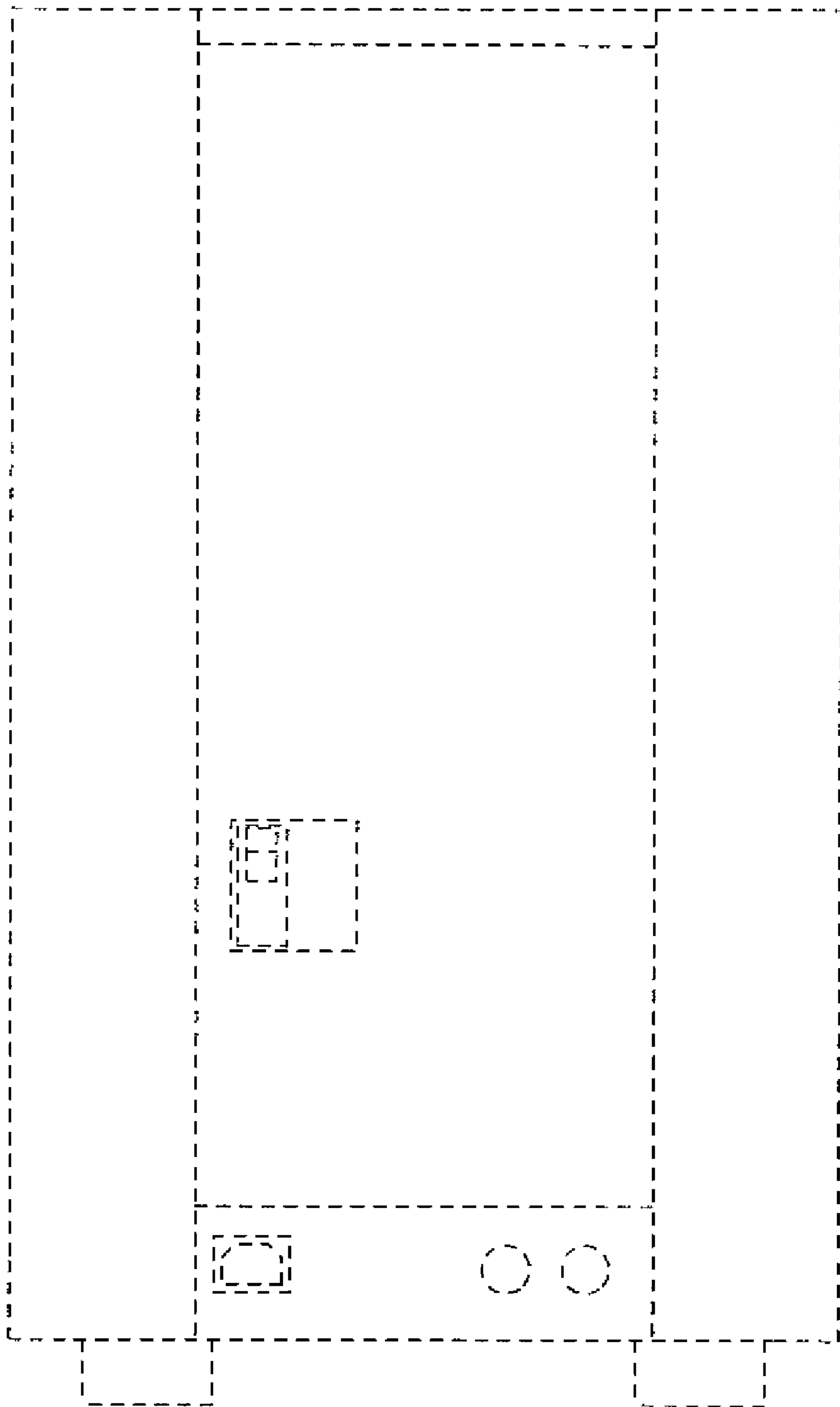


FIG. 3

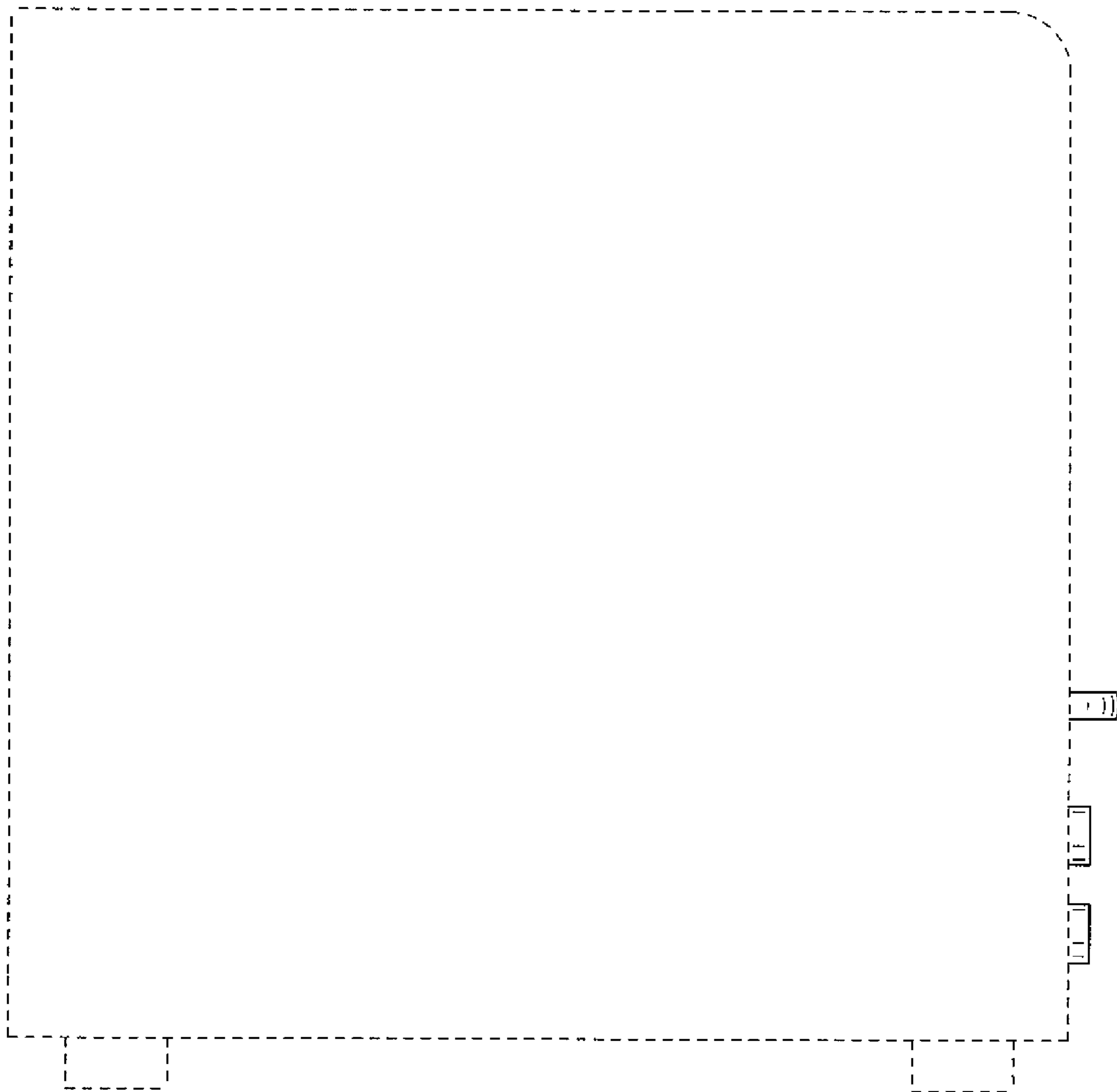


FIG. 4

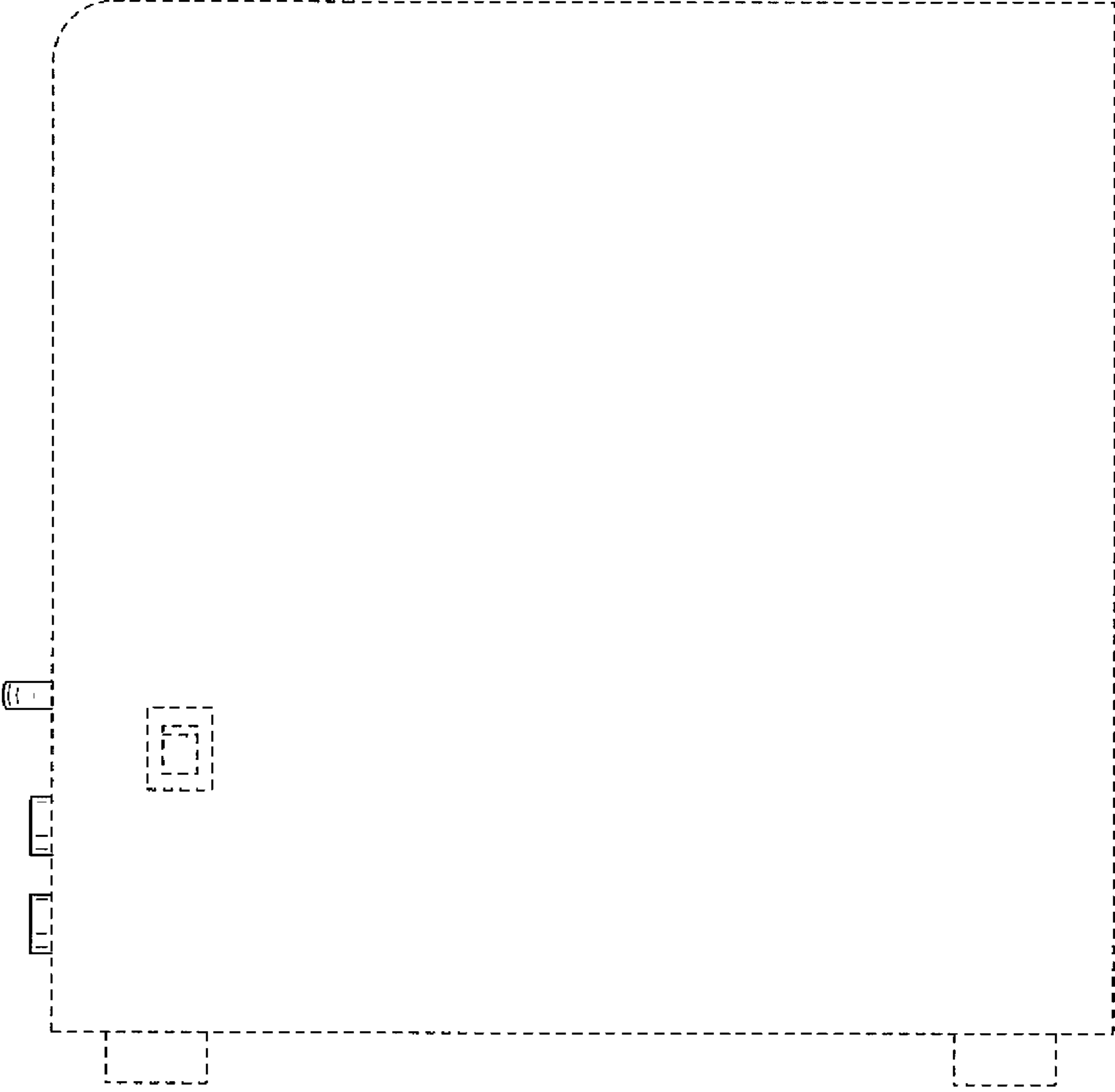


FIG. 5

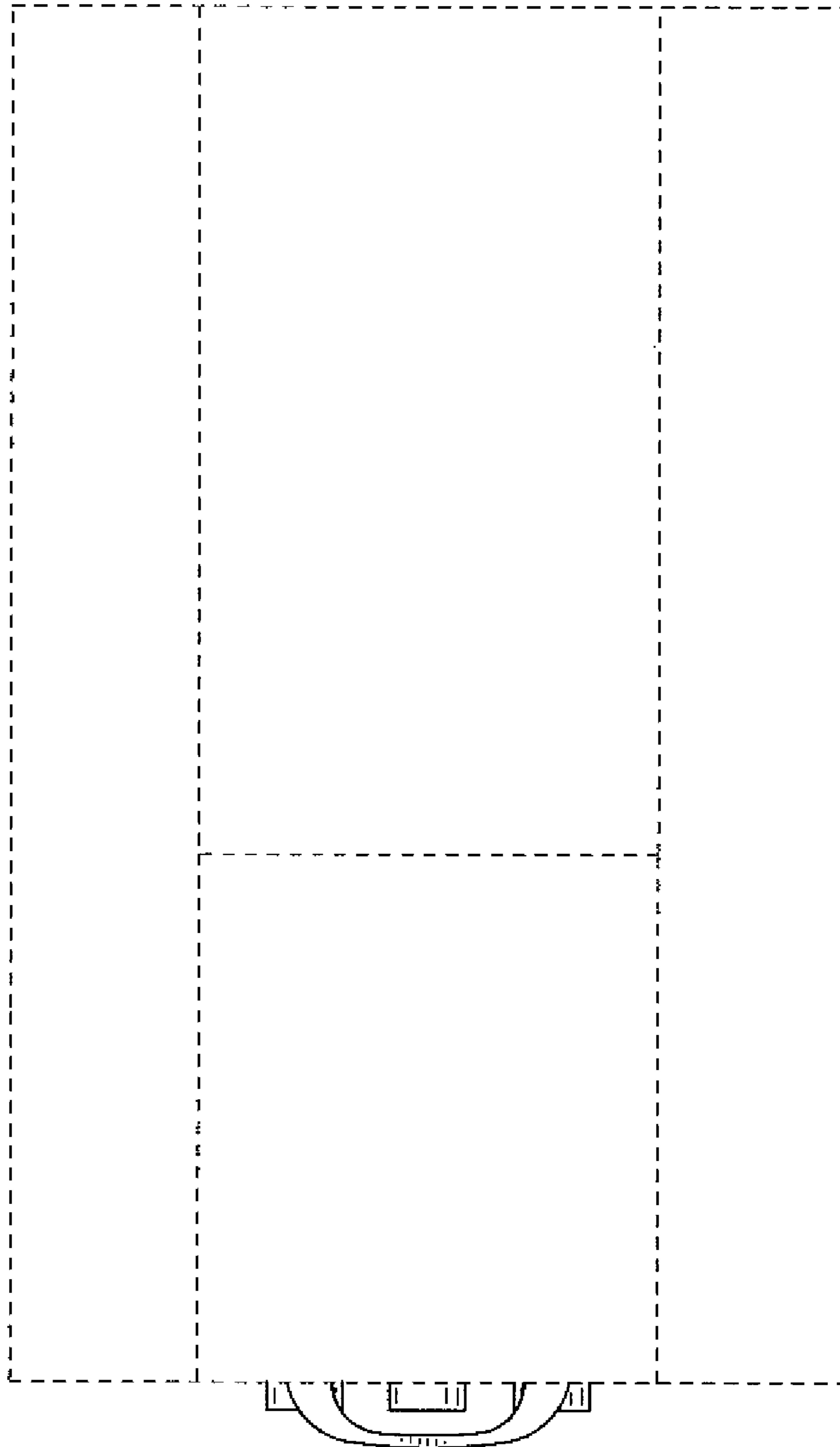


FIG. 6

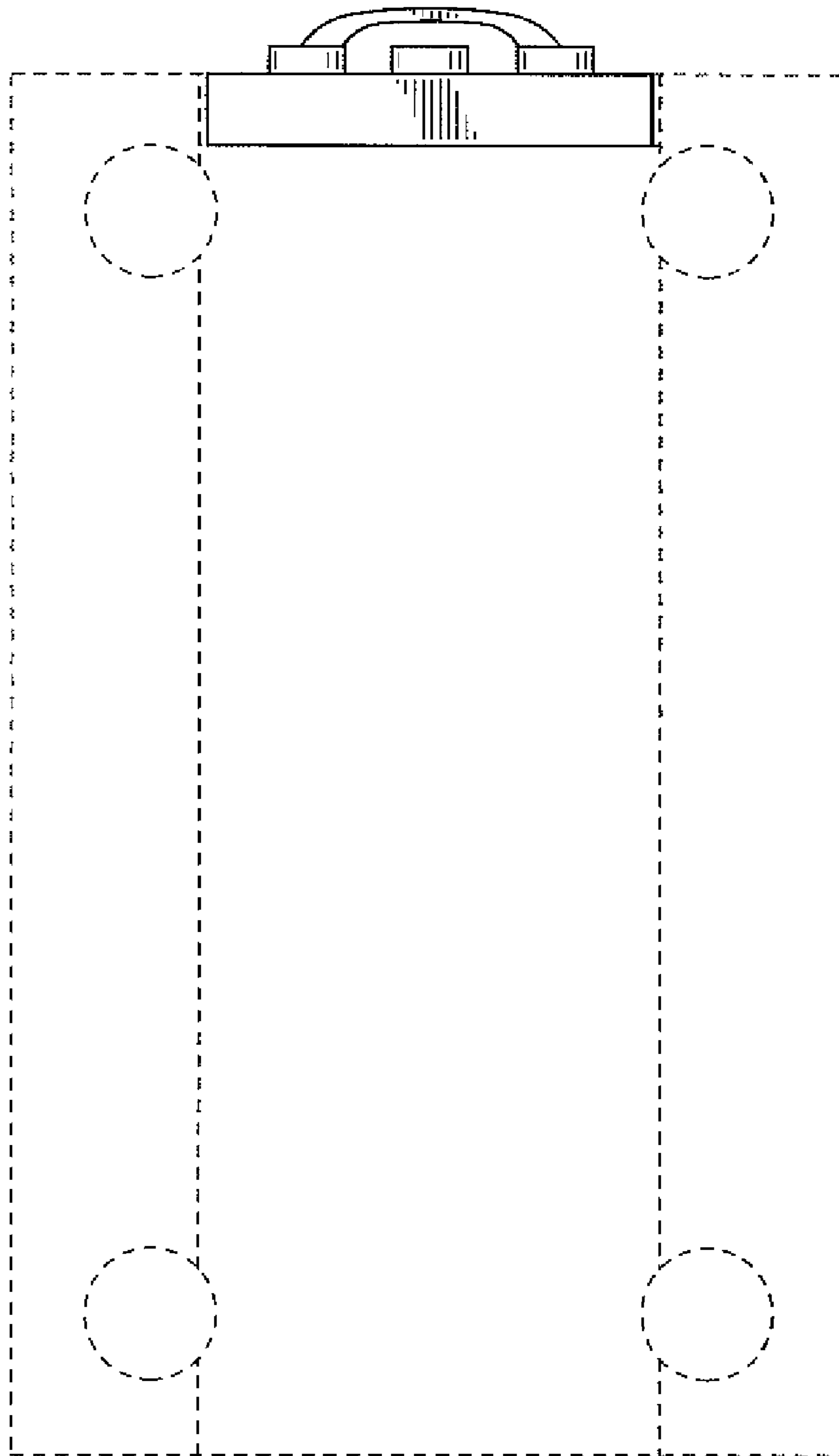


FIG. 7

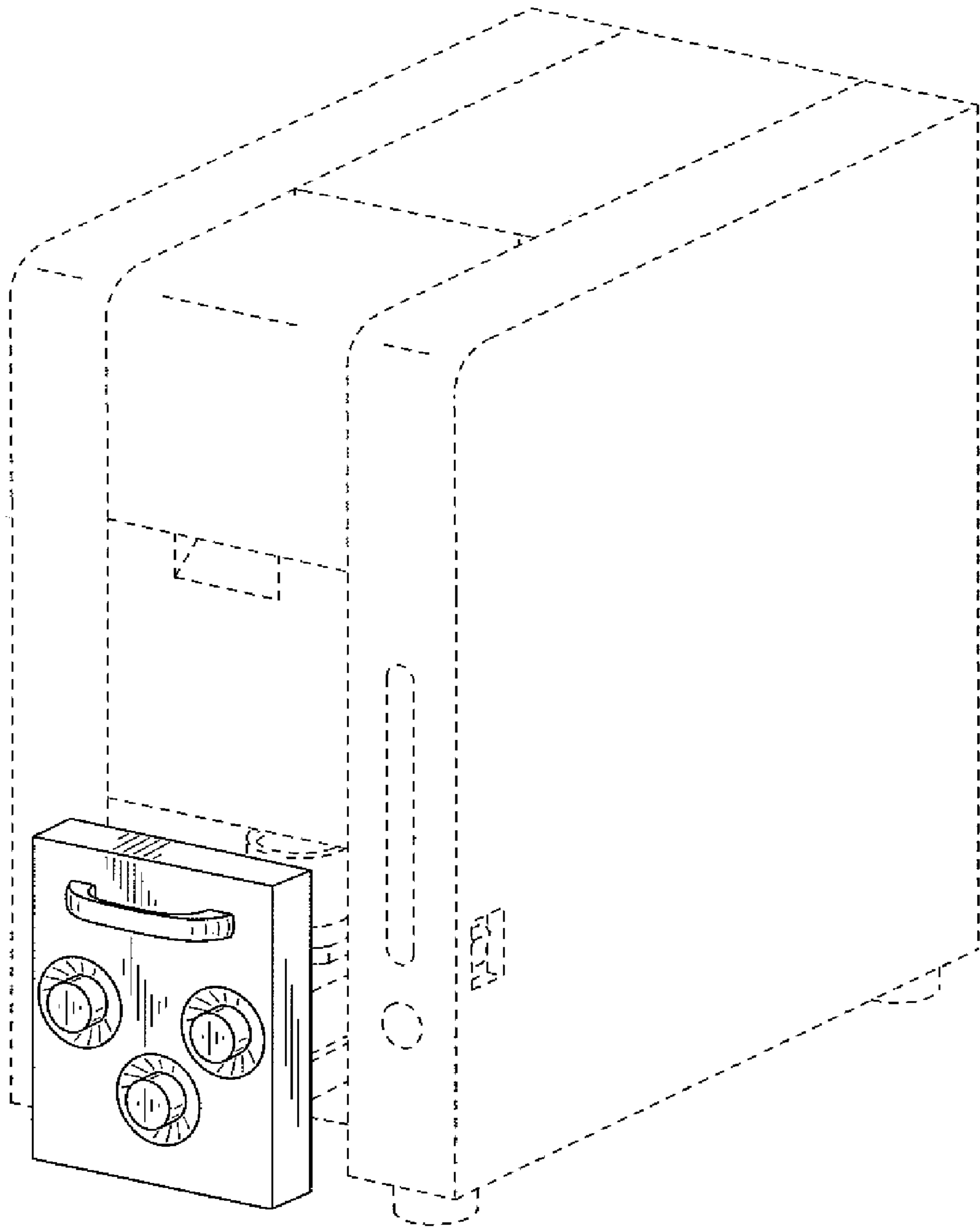


FIG. 8